

# RELIABILITY DATA

## LTC1564 / 1565 / 1566

1/22/2009

### • OPERATING LIFE TEST

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS <sup>(1)</sup> AT +125°C	NUMBER OF <sup>(2)</sup> FAILURES
SOIC/SOT/MSOP	231	9952	0806	231.00	0
SSOP/TSSOP	143	0114	0114	143.00	0
	374			374.00	0

### • PRESSURE COOKER TEST AT 15 PSIG, +121°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
SOIC/SOT/MSOP	250	0004	0104	85.94	0
SSOP/TSSOP	1,145	0138	0837	89.26	0
	1,395			175.19	0

### • TEMP CYCLE FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	150	0004	0101	155.95	0
SSOP/TSSOP	848	0138	0721	179.60	0
	998			335.55	0

### • THERMAL SHOCK FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	100	0004	0004	106.00	0
SSOP/TSSOP	1,042	0210	0811	241.70	0
	1,142			347.70	0

(1) Assumes Activation Energy = 0.7 Electron Volts

(2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 31.65 FITS

(3) Mean Time Between Failures in Years = 3,604

(4) Assumes 20X Acceleration from 85°C to +131°C

Note: 1 FIT = 1 Failure in One Billion Hours.